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DATA SHEET

74F776
Pi-bus transceiver

Product specification

1990 Dec 19

IC15 Data Handbook

Philips
Semiconductors

PHILIPS

FEATURES

- Octal latched transceiver
- Drives heavily loaded backplanes with equivalent load impedances down to 10 ohms
- High drive (100mA) open collector drivers on B port
- Reduced voltage swing (1 volt) produces less noise and reduces power consumption
- High speed operation enhances performance of backplane buses and facilitates incident wave switching
- Compatible with Pi–bus and IEEE 896 Futurebus standards
- Built–in precision band–gap reference provides accurate receiver thresholds and improved noise immunity
- Controlled output ramp and multiple GND pins minimize ground bounce
- Glitch–free power up/power down operation
- Multiple package options
- Industrial temperature range available (–40°C to +85°C)

DESCRIPTION

The 74F776 is an octal bidirectional latched transceiver and is intended to provide the electrical interface to a high performance wired–OR bus. The B port inverting drivers are low–capacitance open collector with controlled ramp and are designed to sink 100mA from 2 volts. The B port inverting receivers have a 100 mV threshold region and a 4ns glitch filter.

The 74F776 B port interfaces to 'Backplane Transceiver Logic' (BTL). BTL features a reduced (1V to 2V) voltage swing for lower power consumption and a series diode on the drivers to reduce capacitive loading. Incident wave switching is employed, therefore BTL propagation delays are short. Although the voltage swing is less for BTL, so is its receiver threshold, therefore noise margins are excellent.

BTL offers low power consumption, low ground bounce, EMI and crosstalk, low capacitive loading, superior noise margin and low propagation delays. This results in a high bandwidth, reliable backplane.

The 74F776 A port has TTL 3–state drivers and TTL receivers with a latch function. A separate high–level control voltage input (V_X) is provided to limit the A side output level to a given voltage level (such as 3.3V). For 5.0V systems, V_X is simply tied to V_{CC}.

The 74F776 has a designed feature to control the B output transitions during power sequencing. There are two possible sequencing, They are as follows:

1.When $\overline{LE}$ = low and $\overline{OEB}$n = low then the B outputs are disabled until the $\overline{LE}$ circuitry takes control. Then the B outputs will follow the A inputs, making a maximum of one transition during power–up (or down).

2. If $\overline{LE}$ = high or $\overline{OEB}$n = high then the B outputs will be disabled during power–up (or down).

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT(TOTAL)
74F776	6.5ns	80mA

ORDERING INFORMATION

DESCRIPTION	ORDER CODE		PKG DWG #
	COMMERCIAL RANGE V_{CC} = 5V ±10%, T_{amb} = 0°C to +70°C	INDUSTRIAL RANGE V_{CC} = 5V ±10%, T_{amb} = –40°C to +85°C	
28–pin plastic DIP (600 mil)	N74F776N	I74F776N	SOT117-2
28–pin PLCC	N74F776A	I74F776A	SOT261-2

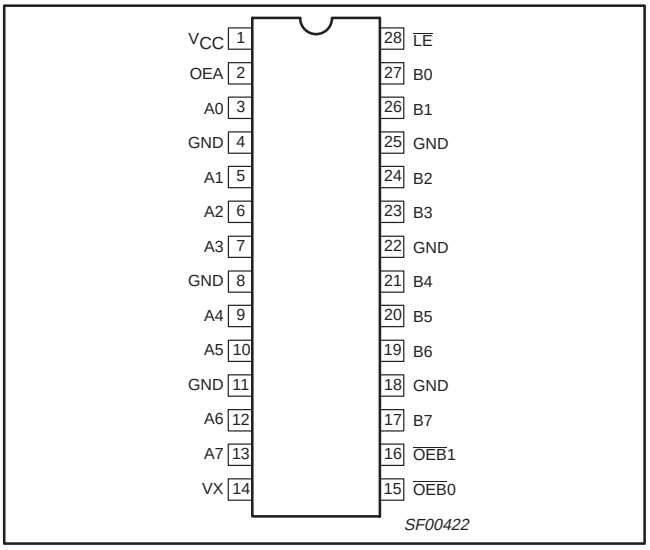
INPUT AND OUTPUT LOADING AND FAN OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A0 – A7	PNP latched inputs	3.5/0.117	70µA/70µA
B0 – B7	Data inputs with threshold circuitry	5.0/0.167	100µA/100µA
OEA	A output enable input (active high)	1.0/0.033	20µA/20µA
$\overline{OEB}$0, $\overline{OEB}$1	B output enable inputs (active low)	1.0/0.033	20µA/20µA
$\overline{LE}$	Latch enable input (active low)	1.0/0.033	20µA/20µA
A0 – A7	3–state outputs	150/40	3mA/24mA
B0 – B7	Open collector outputs	OC/166.7	OC/100mA

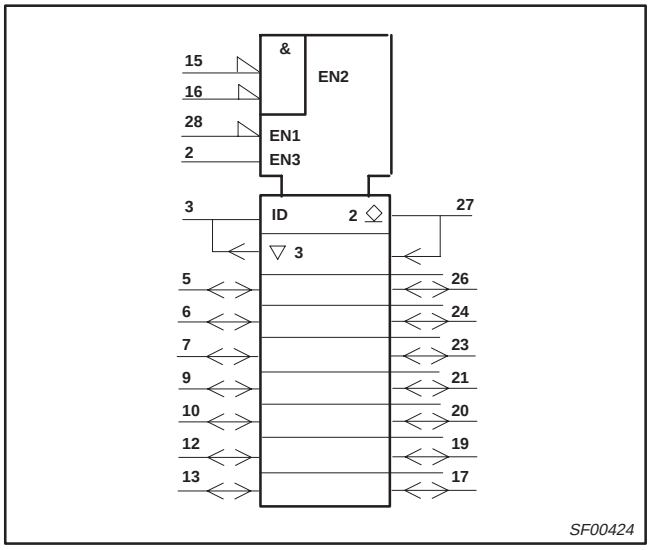
Notes to input and output loading and fan out table

One (1.0) FAST unit load is defined as: 20µA in the high state and 0.6mA in the low state.
OC = Open collector.

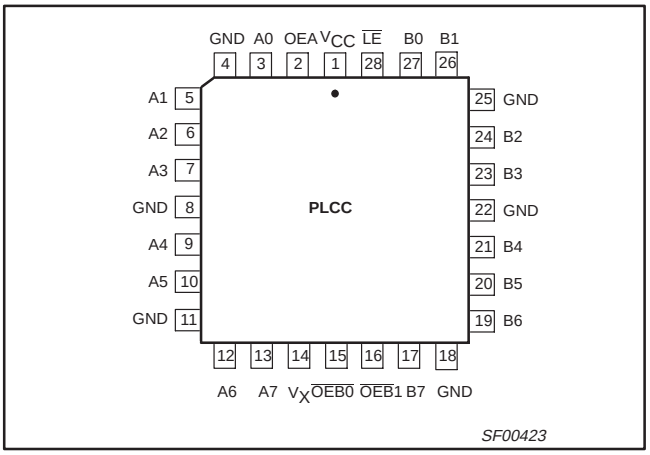
PIN CONFIGURATION



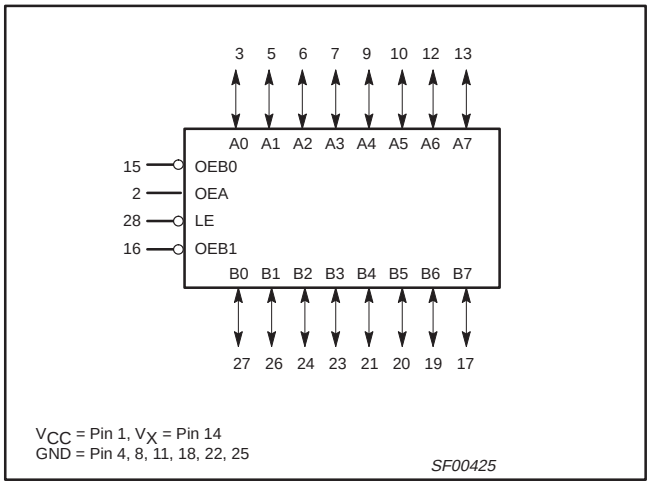
IEC/IEEE SYMBOL



PIN CONFIGURATION PLCC



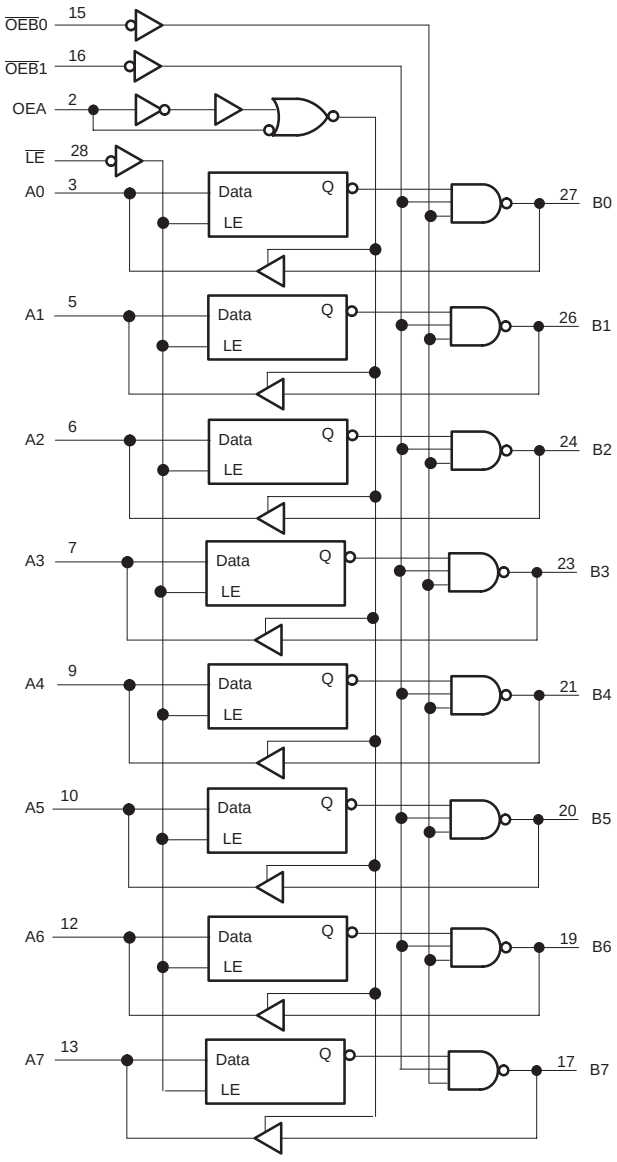
LOGIC SYMBOL



PIN DESCRIPTION

SYMBOL	PINS	TYPE	NAME AND FUNCTION
A0 – A7	3, 5, 6, 7, 9, 10, 12, 13	I/O	PNP latched input/3–state output (with V_X control option)
B0 – B7	27, 26, 24, 23, 21, 20, 19, 17	I/O	Data input with special threshold circuitry to reject noise/ open collector output, high current drive
$\overline{OEB}0$	15	Input	Enables the B outputs when both pins are low
$\overline{OEB}1$	16	Input	
OEA	2	Input	Enables the A outputs when high
$\overline{LE}$	28	Input	Latched when high (a special feature is built in for proper enabling times)
V_X	14	Input	Clamping voltage keeping V_{OH} from rising above V_X ($V_X = V_{cc}$ for normal use)

LOGIC DIAGRAM



V_{CC} = Pin 1, V_X = Pin 14,
GND = Pin 4, 8, 11, 18, 22, 25

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FUNCTION TABLE

INPUTS						LATCH	OUTPUTS		OPERATING MODE
An	Bn*	$\overline{LE}$	OEA	$\overline{OEB}$0	$\overline{OEB}$1	STATE	An	Bn	
H	X	L	L	L	L	H	Z	Z	A 3–state, data from A to B
L	X	L	L	L	L	L	Z	L	
X	X	H	L	L	L	Qn	Z	Qn	A 3–state, latched data to B
–	–	L	H	L	L	(1)	(1)	(1)	Feedback: A to B, B to A
–	H	H	H	L	L	H (2)	H	Z(2)	Preconditioned latch enabling data transfer from B to A
–	L	H	H	L	L	H (2)	L	Z(2)	
–	–	H	H	L	L	Qn	Qn	Qn	Latch state to A and B
H	X	L	L	H	X	H	Z	Z	B and A 3–state
L	X	L	L	H	X	L	Z	Z	
X	X	H	L	H	X	Qn	Z	Z	
–	H	L	H	H	X	H	H	Z	B 3–state, data from B to A
–	L	L	H	H	X	L	L	Z	
–	H	H	H	H	X	Qn	H	Z	
–	L	H	H	H	X	Qn	L	Z	
H	X	L	L	X	H	H	Z	Z	B and A 3–state
L	X	L	L	X	H	L	Z	Z	
X	X	H	L	X	H	Qn	Z	Z	
–	H	L	H	X	H	H	H	Z	B 3–state, data from B to A
–	L	L	H	X	H	L	L	Z	
–	H	H	H	X	H	Qn	H	Z	
–	L	H	H	X	H	Qn	L	Z	

Notes to function table

H = High voltage level
L = Low voltage level
X = Don't care
– = Input not externally driven
Z = High impedance "off" state
Q_n = High or Low voltage level one setup time prior to the low–to–high $\overline{LE}$ transition.
(1) = Condition will cause a feedback loop path: A to B and B to A.
(2) = The latch must be preconditioned such that B inputs may assume a high or low level while $\overline{OEB}$0 and $\overline{OEB}$1 are low and $\overline{LE}$ is high.
B* = Precaution should be taken to insure the B inputs do not float. If they do they are equal to low state.

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V_{CC}	Supply voltage		–0.5 to +7.0	V
V_X	Threshold control		–0.5 to +7.0	V
V_{IN}	Input voltage	$\overline{OEB}$n, OEA, $\overline{LE}$	–0.5 to +7.0	V
		A0 – A7, B0 – B7	–0.5 to +5.5	V
I_{IN}	Input current		–40 to +5	mA
V_{OUT}	Voltage applied to output in high output state		–0.5 to V_{CC}	V
I_{OUT}	Current applied to output in low output state	A0 – A7	48	mA
		B0 – B7	200	mA
T_{amb}	Operating free air temperature range	Commercial range	0 to +70	°C
		Industrial range	–40 to +85	°C
T_{stg}	Storage temperature range		–65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		LIMITS			UNIT
			MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5.0	5.5	V
V_{IH}	High–level input voltage	Except B0 – B7	2.0			V
		B0 – B7	1.6			V
V_{IL}	Low–level input voltage	Except B0 – B7			0.8	V
		B0 – B7			1.45	V
I_{Ik}	Input clamp current	Except A0 – A7			–18	mA
		A0 – A7			–40	mA
I_{OH}	High–level output current	A0 – A7			–3	mA
I_{OL}	Low–level output current	A0 – A7			24	mA
		B0 – B7			100	mA
T_{amb}	Operating free air temperature range	Commercial range	0		+70	°C
		Industrial range	–40		+85	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS[1]		LIMITS			UNIT
					MIN	TYP[2]	MAX	
I_{OH}	High–level output current	B0 – B7	V_{CC} = MAX, V_{IL} = MAX, V_{IH} = MIN, V_{OH} = 2.1V				100	µA
I_{OFF}	Power–off output current	B0 – B7	V_{CC} = 0.0V, V_{IL} = MAX, V_{IH} = MIN, V_{OH} = 2.1V				100	µA
V_{OH}	High-level output voltage	A0 – A7[4]	V_{CC} = MIN,	I_{OH} = –3mA, V_X =V_{CC}	2.5		V_{CC}	V
			V_{IL} = MAX, V_{IH} = MIN	I_{OH} = –4mA, V_X =3.13V and 3.47V	2.5			V
V_{OL}	Low-level output voltage	A0 – A7[4]	V_{CC} = MIN,	I_{OL} = 20mA, V_X = V_{CC}			0.50	V
		B0 – B7	V_{IL} = MAX	I_{OL} = 100mA			1.15	V
			V_{IH} = MIN	I_{OL} = 4mA	0.40			V
V_{IK}	Input clamp voltage	A0 – A7	V_{CC} = MIN, I_I = I_{IK}				-0.5	V
		Except A0 – A7	V_{CC} = MIN, I_I = I_{IK}				-1.2	V
I_I	Input current at	$\overline{OEB}$n, OEA, $\overline{LE}$	V_{CC} = 0.0V, V_I = 7.0V				100	µA
	maximum input voltage	A0 – A7, B0 – B7	V_{CC} = MAX, V_I = 5.5V				1	mA
I_{IH}	High–level input current	$\overline{OEB}$n, OEA, $\overline{LE}$	V_{CC} = MAX, V_I = 2.7V, Bn –An =0V				20	µA
		B0 – B7	V_{CC} = MAX, V_I = 2.1V				100	µA
I_{IL}	Low–level input current	$\overline{OEB}$n, OEA, $\overline{LE}$	V_{CC} = MAX, V_I = 0.5V				–20	µA
		B0 – B7	V_{CC} = MAX, V_I = 0.3V				–100	µA
I_{OZH} + I_{IH}	Off state output current, high level voltage applied	A0 – A7	V_{CC} = MAX, V_O = 2.7V				70	µA
I_{OZL} + I_{IL}	Off state output current, low level voltage applied	A0 – A7	V_{CC} = MAX, V_O = 0.5V				–70	µA
I_X	High–level control current		V_{CC} = MAX, V_X = V_{CC}, $\overline{LE}$ = OEA = $\overline{OEB}$n = 2.7V, A0 – A7 = 2.7V, B0 – B7 = 2.0V,		–100		100	µA
			V_{CC} = MAX, V_X = 3.13 & 3.47V, $\overline{LE}$ = OEA = 2.7V, $\overline{OEB}$n = A0 – A7 = 2.7V, B0 – B7 = 2.0V,		–10		10	µA
I_{OS}	Short circuit output current[3]	A0 – A7 only	V_{CC} = MAX, Bn = 1.8V, OEA = 2.0V, $\overline{OEB}$n = 2.7V		-60		-150	mA
I_{CC}	Supply current (total)	I_{CCH}	V_{CC} = MAX			65	100	mA
		I_{CCL}	V_{CC} = MAX, V_{IL} = 0.5V			100	145	mA
		I_{CCZ}				75	100	mA

Notes to DC electrical characteristics

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. Unless otherwise specified, V_X = V_{CC} for all test conditions.
2. All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.
4. Due to test equipment limitations, actual test conditions are for V_{IH} =1.8v and V_{IL} = 1.3V.

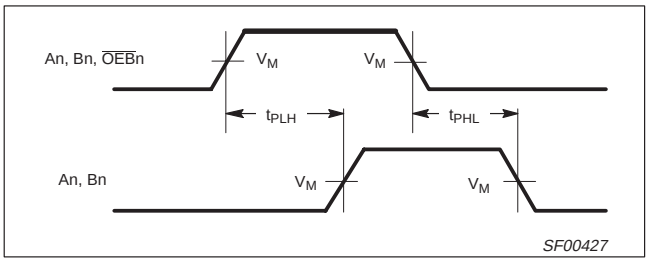
AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	A PORT LIMITS							UNIT
			T_{amb} = +25°C V_{CC} = +5.0V C_L = 50pF, R_L = 500Ω			T_{amb} = 0°C to +70°C V_{CC} = +5.0V ± 10% C_L = 50pF, R_L = 500Ω		T_{amb} = –40°C to +85°C V_{CC} = +5.0V ± 10% C_L = 50pF, R_L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH} t_{PHL}	Propagation delay Bn to An	Waveform 1	5.5 4.5	8.0 6.0	12.0 9.0	5.5 4.5	12.0 9.0	5.5 4.5	12.0 9.0	ns
t_{PZH} t_{PZL}	Output enable time to high or low, OEA to An	Waveform 3, 4	8.0 8.5	10.5 11.0	13.5 13.5	7.5 8.0	15.0 15.5	7.5 8.0	15.5 15.5	ns
t_{PHZ} t_{PLZ}	Output disable time from high or low, OEA to An	Waveform 3, 4	2.0 2.0	3.5 4.5	6.0 7.0	1.5 2.0	6.5 7.5	1.5 2.0	6.5 7.5	ns
SYMBOL	PARAMETER	TEST CONDITION	B PORT LIMITS							UNIT
			T_{amb} = +25°C V_{CC} = +5.0V C_D = 30pF, R_U = 9Ω			T_{amb} = 0°C to +70°C V_{CC} = +5.0V ± 10% C_D = 30pF, R_U = 9Ω		T_{amb} = –40°C to +85°C V_{CC} = +5.0V ± 10% C_D = 30pF, R_U = 9Ω		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH} t_{PHL}	Propagation delay An to Bn	Waveform 1	3.0 3.0	5.0 4.5	7.0 7.5	2.5 2.5	8.0 8.5	2.0 2.5	9.0 8.5	ns
t_{PLH} t_{PHL}	Propagation delay $\overline{LE}$ to Bn	Waveform 1	3.5 3.5	5.0 5.0	8.0 8.0	3.0 2.5	9.0 9.0	2.5 2.5	9.5 9.5	ns
t_{PLH} t_{PHL}	Enable/disable time $\overline{OEB}$n to An	Waveform 1	3.0 3.5	4.5 5.5	7.0 9.0	2.5 3.5	8.0 10.0	2.5 3.5	8.5 10.5	ns
t_{TLH} t_{THL}	Transition time, B port 1.3V to 1.7V, 1.7V to 1.3V	Test Circuit and Waveforms	0.5 0.5	2.0 2.0	4.5 4.5	0.5 0.5	5.0 4.5	0.5 0.5	5.0 4.5	ns

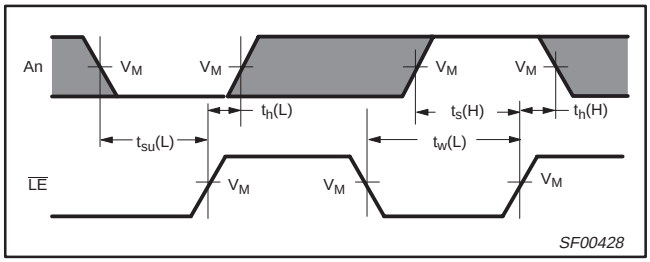
AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS							UNIT
			T_{amb} = +25°C V_{CC} = +5.0V C_L = 50pF, R_L = 500Ω			T_{amb} = 0°C to +70°C V_{CC} = +5.0V ± 10% C_L = 50pF, R_L = 500Ω		T_{amb} = –40°C to +85°C V_{CC} = +5.0V ± 10% C_L = 50pF, R_L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{su} (H) t_{su} (L)	Setup time, high or low An to $\overline{LE}$	Waveform 2	3.5 4.5			4.5 5.0		4.5 5.0		ns
t_h(H) t_h(L)	Hold time, high or low An to $\overline{LE}$	Waveform 2	0.0 0.0			0.0 0.0		0.0 0.0		ns
t_w (L)	$\overline{LE}$ pulse width, low	Waveform 2	4.0			5.0		5.0		ns

AC WAVEFORMS

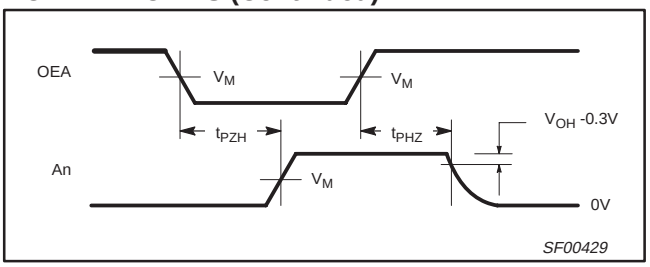


Waveform 1. Propagation delay for data to output

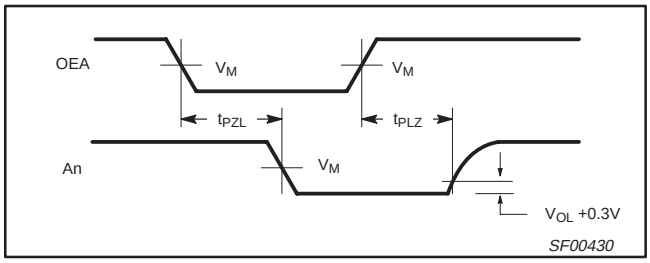


Waveform 2. Data setup and hold times and $\overline{LE}$ pulse width

AC WAVEFORMS (Continued)



Waveform 3. 3-state output enable time to high level and output disable time from high level



Waveform 4. 3-state output enable time to low level and output disable time from low level

Notes to AC waveforms

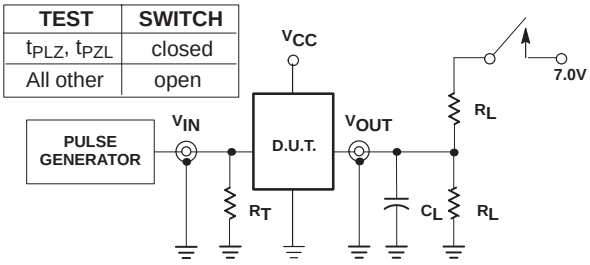
For all waveforms, V_M = 1.5V.

The shaded areas indicate when the input is permitted to change for predictable output performance.

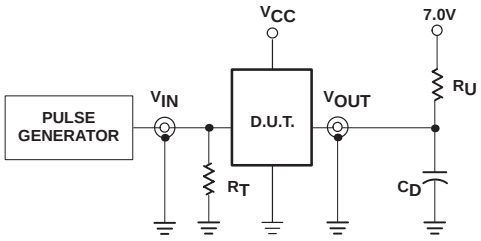
TEST CIRCUIT AND WAVEFORMS

SWITCH POSITION

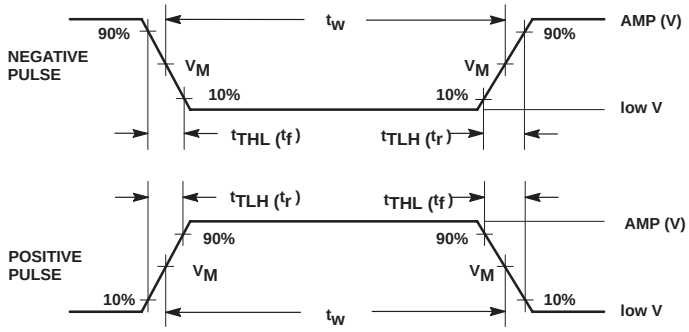
TEST	SWITCH
t_{PLZ}, t_{PZL}	closed
All other	open



Test circuit for 3–State outputs on A port



Test circuit for outputs on B port



Input pulse definition

family	INPUT PULSE REQUIREMENTS						
	amplitude	Low V	V_M	rep. rate	t_w	t_{TLH}	t_{THL}
A port	3.0V	0.0V	1.5V	1MHz	500ns	2.5ns	2.5ns
B port	2.0V	1.0V	1.0V	1MHz	500ns	4.0ns	4.0ns

DEFINITIONS:

R_L = Load resistor; see AC electrical characteristics for value.
C_L = Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.
R_U = Pull up resistor; see AC electrical characteristics for value.
C_D = Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.
R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

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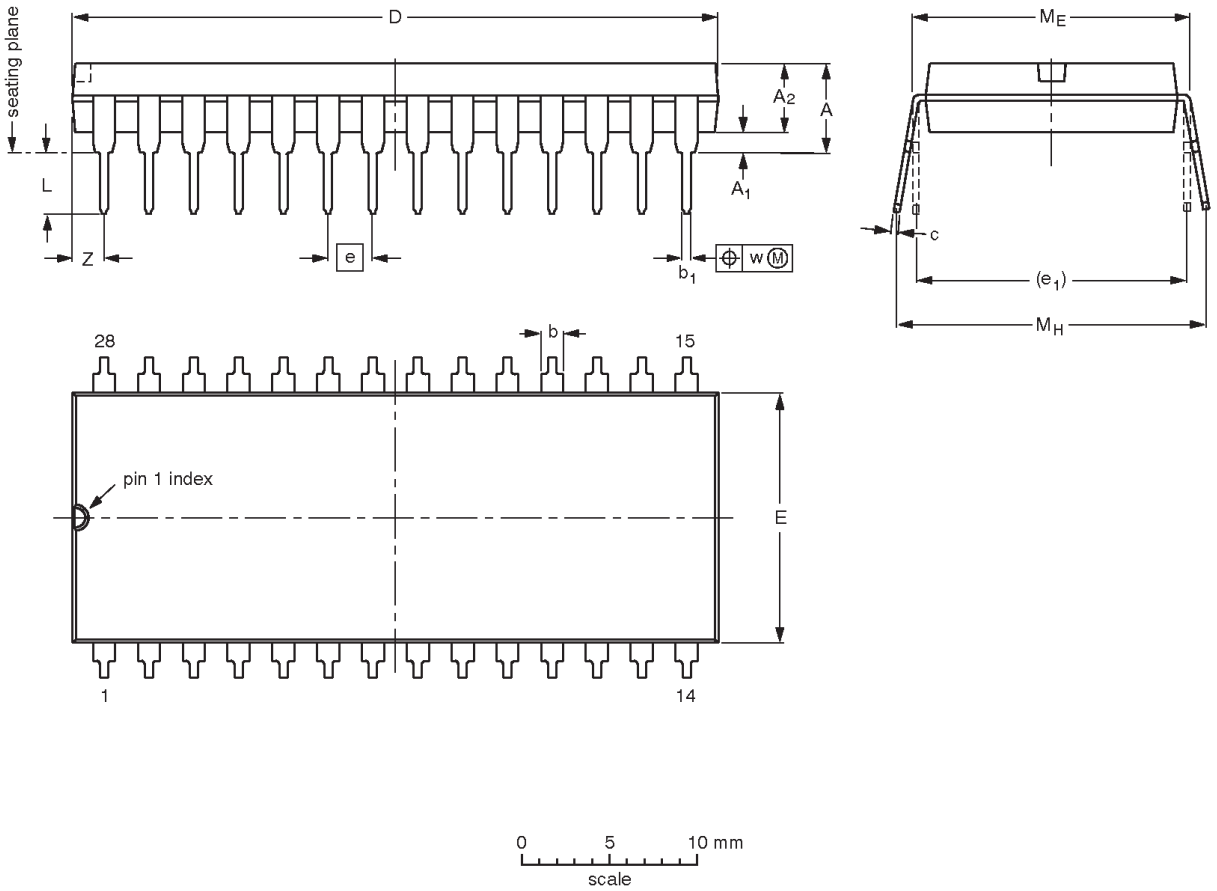
DIP28: plastic dual in-line package; 28 leads (600 mil); long body **SOT117-2**



DIMENSIONS (millimetre dimensions are derived from the original inch dimensions)

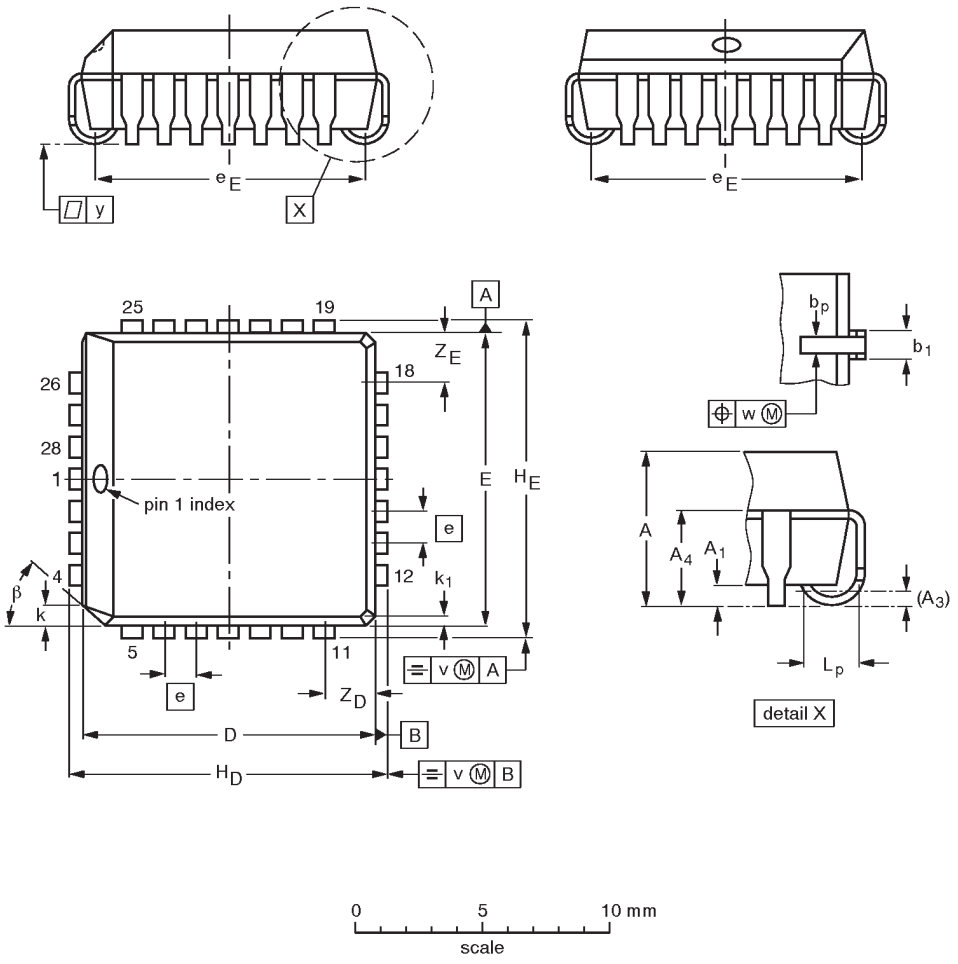
UNIT	A max.	A_1 min.	A_2 max.	b	b_1	c	D (1)	E (1)	e	e_1	L	M_E	M_H	w	Z (1) max.
mm	5.08	0.51	3.94	1.63 1.14	0.56 0.43	0.38 0.25	37.08 35.94	14.22 13.84	2.54	15.24	3.51 3.05	15.75 15.24	17.65 15.24	0.25	2.10
inches	0.200	0.020	0.155	0.064 0.045	0.022 0.017	0.015 0.010	1.460 1.415	0.560 0.545	0.100	0.600	0.138 0.120	0.62 0.60	0.695 0.600	0.01	0.083

Note

1. Plastic or metal protrusions of 0.01 inches maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT117-2		MS-011AB				95-03-11

PLCC28: plastic leaded chip carrier; 28 leads SOT261-2



DIMENSIONS (millimetre dimensions are derived from the original inch dimensions)

UNIT	A	A_1 min.	A_3	A_4 max.	b_p	b_1	$D^{(1)}$	$E^{(1)}$	e	e_D	e_E	H_D	H_E	k	k_1 max.	L_p	v	w	y	$Z_D^{(1)}$ max.	$Z_E^{(1)}$ max.	β
mm	4.57 4.19	0.51	0.25	3.05	0.53 0.33	0.81 0.66	11.58 11.43	11.58 11.43	1.27	10.92 9.91	10.92 9.91	12.57 12.32	12.57 12.32	1.22 1.07	0.51	1.44 1.02	0.18	0.18	0.10	2.16	2.16	45°
inches	0.180 0.165	0.020	0.01	0.12	0.021 0.013	0.032 0.026	0.456 0.450	0.456 0.450	0.05	0.430 0.390	0.430 0.390	0.495 0.485	0.495 0.485	0.048 0.042	0.020	0.057 0.040	0.007	0.007	0.004	0.085	0.085	

Note

1. Plastic or metal protrusions of 0.01 inches maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT261-2						~~92-11-17~~ 95-02-25

Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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print code Date of release: 10-98

Document order number: 9397-750-05177

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